

Notice of References CitedApplication/Control No.
09/883,190Applicant(s)/Patent Under
Reexamination
JAIN ET AL.Examiner
John P TrimmingsArt Unit
2133

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-4,044,244	08-1977	Foreman et al.	714/724
	C	US-5,951,704	09-1999	Sauer et al.	714/736
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NON-PATENT DOCUMENTS

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	U	G. Cauffet et al., Digital Oscilloscope Measurements in High Frequency Power Electronics, IEEE, reference 0-7803-0640-6/92, pages 445 - 447.
	V	Andrew Grochowski et al., Integrated Circuit Testing for Quality Assurance in Manufacturing: History, Current Status, and Future Trends, 1997, IEEE Transactions on Circuits and Systems-II: Analog and Digital Signal Processing, Vol 44, No. 8, August 1997
	W	Information relating to differential oscilloscope usage, interfaces using GPIB, and eye diagram outputs; http://www.tek.com/site/ps/0,,55-16615-SPECS_EN,00.html
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.